## Notice of References Cited Application/Control No. 10/706,975 Examiner Oanh Duong Applicant(s)/Patent Under Reexamination TAM ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0162818	08-2004	Shaw, Venson M.	707/003 ·
*	В	US-2004/0053604	03-2004	Ratilainen et al.	455/414.2
*	С	US-6,047,056	04-2000	Patel, Mahesh	379/221.13
*	D	US-2005/0064883	03-2005	Heck et al.	455/466
*	E	US-6,021,126	02-2000	White et al.	370/352
*	F	US-2005/0259652	11-2005	Tang et al.	370/389
*	G	US-2002/0169823	11-2002	Coulombe et al.	709/203
	н	US-	·		
	ı	US-			
	J	US-			
	К	US-		V	
	L	US-		·	
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1255416 A1	11-2002	European Patent	LAUMEN et al.	
	0					
	Р		•			
	Q					
	R					
	s				·	
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
,	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

